

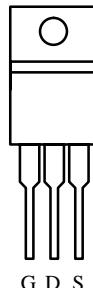
N-Channel Enhancement-Mode Transistors

Product Summary

V _{(BR)DSS} (V)	r _{D(on)} (Ω)	I _D (A)
60	0.014	70 ^a

175°C Rated
Maximum Junction Temperature

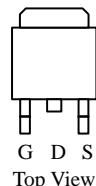
TO-220AB



DRAIN connected to TAB

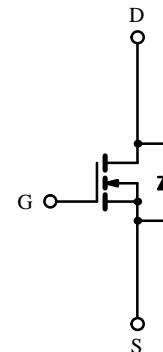
Top View

TO-263



SUB70N06-14

SUP70N06-14



N-Channel MOSFET

Absolute Maximum Ratings (T_C = 25°C Unless Otherwise Noted)

Parameter	Symbol	Limit	Unit
Gate-Source Voltage	V _{GS}	± 20	V
Continuous Drain Current (T _J = 175°C)	I _D	70 ^a	A
T _C = 100°C		49	
Pulsed Drain Current	I _{DM}	160	
Avalanche Current	I _{AR}	70	
Repetitive Avalanche Energy ^b	E _{AR}	180	mJ
Power Dissipation	P _D	142 ^c	W
T _A = 25°C (TO-263) ^d		3.7	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 175	°C

Thermal Resistance Ratings

Parameter	Symbol	Limit	Unit
Junction-to-Ambient	R _{thJA}	40	°C/W
PCB Mount (TO-263) ^d		62.5	
Junction-to-Case	R _{thJC}	1.05	

Notes:

- a. Package limited.
- b. Duty cycle $\leq 1\%$.
- c. See SOA curve for voltage derating.
- d. When mounted on 1" square PCB (FR-4 material).

Subsequent updates to this data sheet may be obtained via facsimile by calling Siliconix FaxBack, 1-408-970-5600. Please request FaxBack document # 1487. A SPICE Model data sheet is available for this product (FaxBack document #5133).

SUP/SUB70N06-14

TEMIC
Semiconductors

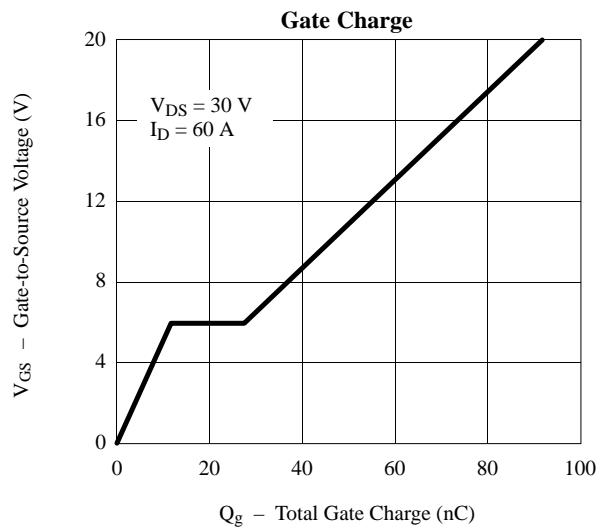
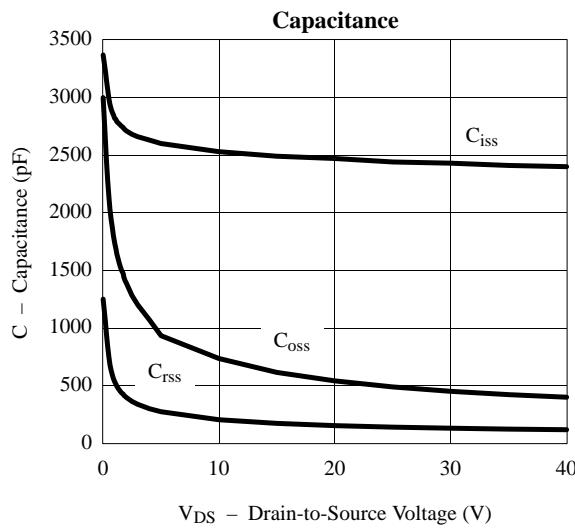
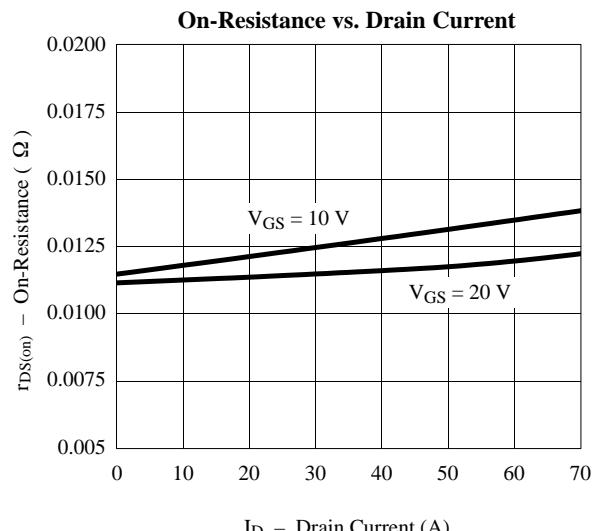
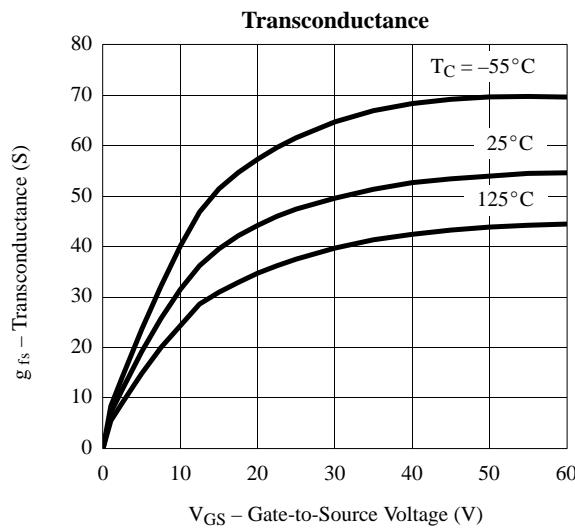
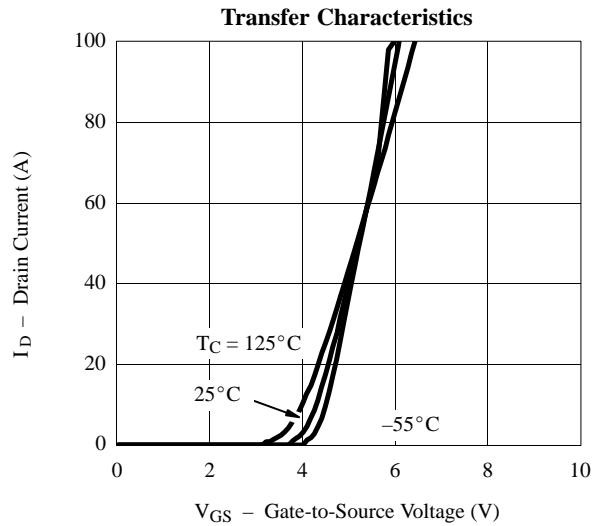
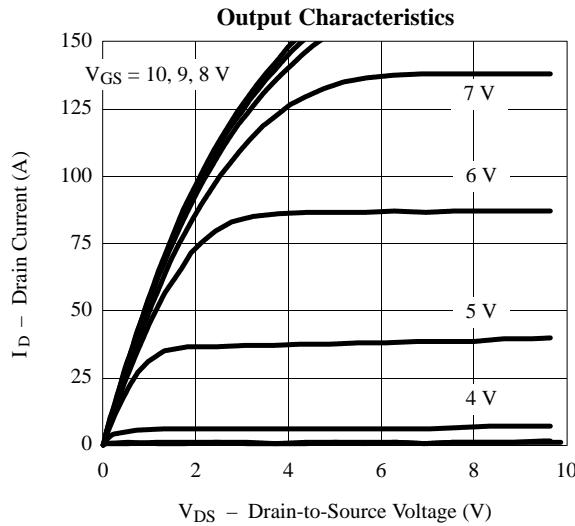
Specifications ($T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_{DS} = 1 \text{ mA}$	2.0	3.0	4.0	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$			1	
		$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125^\circ\text{C}$			50	μA
		$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 175^\circ\text{C}$			150	
On-State Drain Current ^b	$I_{D(\text{on})}$	$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	70			A
Drain-Source On-State Resistance ^b	$r_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$			0.014	
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}, T_J = 125^\circ\text{C}$			0.023	Ω
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}, T_J = 175^\circ\text{C}$			0.028	
Forward Transconductance ^b	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 30 \text{ A}$	25	50		S
Dynamic^a						
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$		2400		pF
Output Capacitance	C_{oss}			490		
Reversen Transfer Capacitance	C_{rss}			130		
Total Gate Charge ^c	Q_g	$V_{DS} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 60 \text{ A}$		45	70	nC
Gate-Source Charge ^c	Q_{gs}			12		
Gate-Drain Charge ^c	Q_{gd}			16		
Turn-On Delay Time ^c	$t_{d(\text{on})}$	$V_{DD} = 30 \text{ V}, R_L = 0.47 \Omega$ $I_D \approx 60 \text{ A}, V_{GEN} = 10 \text{ V}, R_G = 2.5 \Omega$		13	30	ns
Rise Time ^c	t_r			11	30	
Turn-Off Delay Time ^c	$t_{d(\text{off})}$			30	60	
Fall Time ^c	t_f			11	25	
Source-Drain Diode Ratings and Characteristics ($T_C = 25^\circ\text{C}$)^a						
Continuous Current	I_s				70	A
Pulsed Current	I_{SM}				160	
Forward Voltage ^b	V_{SD}	$I_F = 70 \text{ A}, V_{GS} = 0 \text{ V}$			1.4	V
Reverse Recovery Time	t_{rr}	$I_F = 60 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}$		47		ns
Peak Reverse Recovery Current	$I_{RM(\text{REC})}$			3.5		A
Reverse Recovery Charge	Q_{rr}			0.08		μC

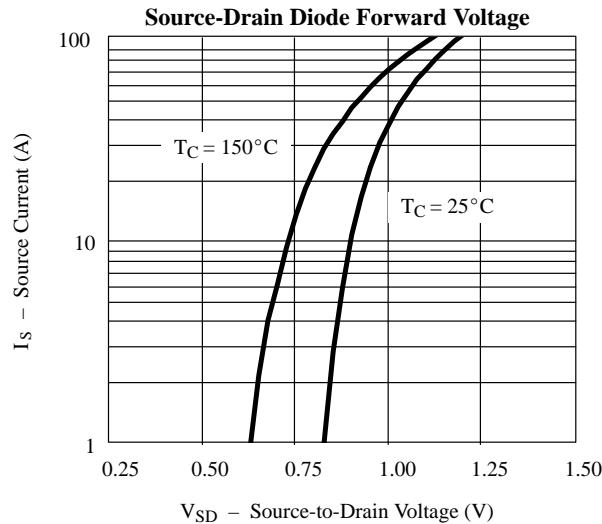
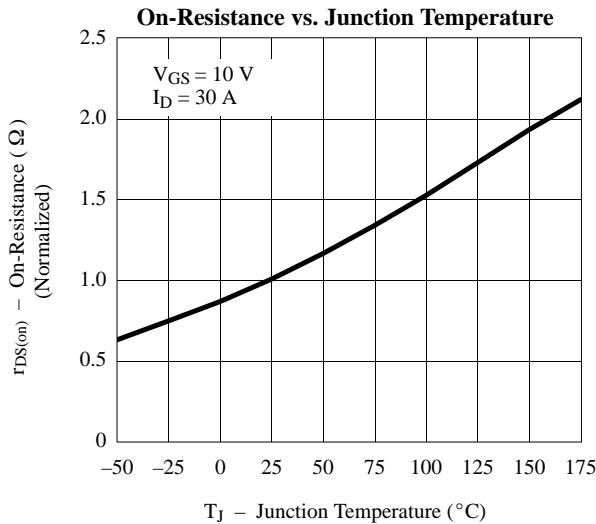
Notes:

- a. Guaranteed by design, not subject to production testing.
- b. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.
- c. Independent of operating temperature.

Typical Characteristics (25°C Unless Otherwise Noted)



Typical Characteristics (25°C Unless Otherwise Noted)



Thermal Ratings

